

## FDS2170N7

# 200V N-Channel PowerTrench® MOSFET

### **General Description**

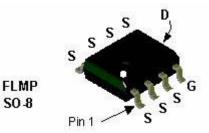
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low  $R_{\text{DS(ON)}}$  in a small package.

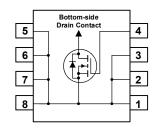
### **Applications**

- · Synchronous rectifier
- DC/DC converter

#### **Features**

- 3.0 A, 200 V.  $R_{DS(ON)}$  = 128 m $\Omega$  @  $V_{GS}$  = 10 V
- High performance trench technology for extremely low  $R_{\mbox{\scriptsize DS}(\mbox{\scriptsize ON})}$
- High power and current handling capability
- Fast switching, low gate charge (26nC typical)
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		200	V
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	3.0	А
	– Pulsed		20	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	3.0	W
		(Note 1b)	1.8	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

## **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDS2170N7	FDS2170N7	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	urce Avalanche Ratings		I	1		1
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, V <sub>DD</sub> = 200 V, I <sub>D</sub> =10 A			400	mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				10	Α
Off Char	acteristics			•		
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	200			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		231		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 160 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V			-100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	4	4.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		-10		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V},  I_D = 3.0 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 3.0 \text{ A}, T_J = 125^{\circ}\text{C}$		107 213	128 268	mΩ
<b>g</b> FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 3.0 \text{ A}$		15		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 100 \text{ V},  V_{GS} = 0 \text{ V},$		1292		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		72		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			24		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.5		Ω
Switchin	g Characteristics (Note 2)					
$t_{d(on)}$	Turn-On Delay Time	V <sub>DD</sub> = 100 V, I <sub>D</sub> = 1 A,		12	22	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		5	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			30	48	ns
t <sub>f</sub>	Turn-Off Fall Time			23	36	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 100 \text{ V},  I_{D} = 3.0 \text{ A},$		26	36	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		7		nC
$Q_{gd}$	Gate-Drain Charge			10		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain–Source				2.5	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.5 A (Note 2)		0.76	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 3.0A		95		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$ (Note 2)		552		nC

1. R<sub>0,JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0,UC</sub> is guaranteed by design while R<sub>0,CA</sub> is determined by the user's board design.



a) 40°C/W when mounted on a 1in² pad of 2 oz copper



b) 85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300 $\mu s,$  Duty Cycle < 2.0%

## **Dimensional Outline and Pad Layout** -(0.65)(3.68)DRAIN TERMINAL -0.75 MIN (0.67)(2.36)DRAIN 2.80 MIN TERMINAL 7.40 8 5 0.70 BOTTOM VIEW 1.50 MIN 4 4.90±0.10-1.27 1.40 3.81 - 3.81 В -4.10 MIN-LAND PATTERN RECOMMENDATION 3.90±0.10 SEE DETAIL A 0.51 (0.34) -**⊕** 0.127**M** B A 6.00±0.20-NOTES: UNLESS OTHERWISE SPECIFIED △ 0.1 C A) ALL DIMENSIONS ARE IN MILLIMETERS. STANDARD LEAD FINISH: 20-80 MICROINCHES NICKEL/ 6 MICROINCHES MAX. PALLADIUM AND GOLD FLASH. C) NO JEDEC REGISTERED REFERENCE AS OF MARCH 2, 2000. -0.50 X 45° GAGE PLANE 0.36 1.60 MAX \_0.10 \_0.00 0.90 SEATING PLANE <del>-</del> (1.04) <del>|-</del> <u>DETAIL</u> A SCALE: 24:1

## **Typical Characteristics**

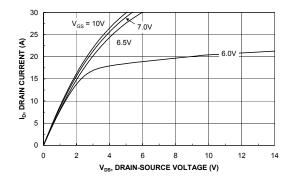


Figure 1. On-Region Characteristics.

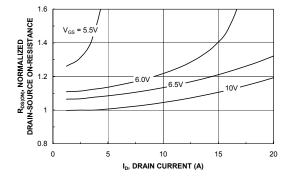


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

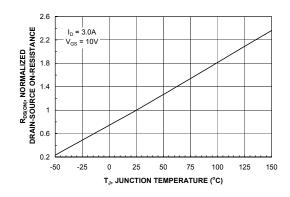


Figure 3. On-Resistance Variation with Temperature.

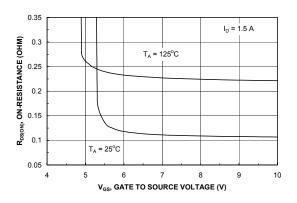


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

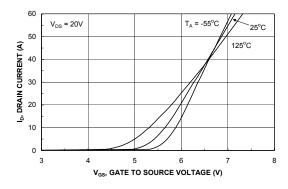


Figure 5. Transfer Characteristics.

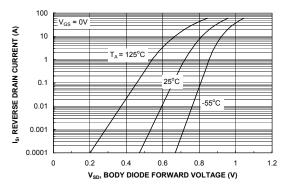
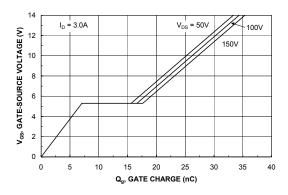


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

## **Typical Characteristics**



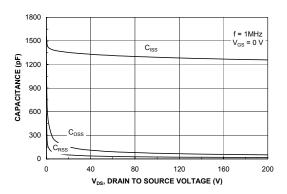


Figure 7. Gate Charge Characteristics.

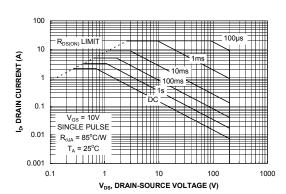


Figure 8. Capacitance Characteristics.

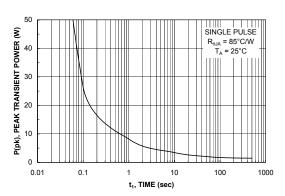


Figure 9. Maximum Safe Operating Area.



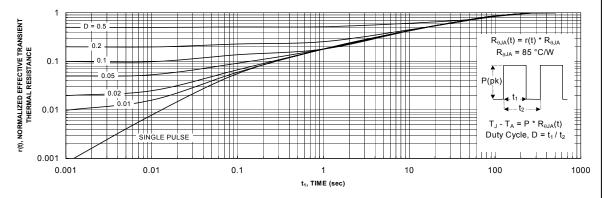


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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